

JAIMA Conferences 2007

Technical Program

August 28(Tues)~August 31(Fri) 10:00AM~5:00PM

International Conference Hall, Makuhari Messe

Organizer:

**Japan Analytical Instruments Manufacturers' Association
(JAIMA)**



<http://www.jaimashow.jp/english>

A message from the conference committee chairman 2007

The JAIMA conference 2007 on analytical instrumentation and material characterization is held with the JAIMA Show 2007. The conference will be held for four days until August 28th – 31st. The JAIMA forum, the key meeting of this conference, held on under the theme; “Instrumental Analysis will enhanced old fine art studies in historical culture investigation”

This conference takes a unique organization and execution style. 18 organizations, academic societies and professional association etc. provide the seminars, symposia, and workshops. Various courses will held from beginner to exports and various field programs provided; Instrumental analysis, analytical instrumentation, material science, environmental analysis and cutting edge technology used analytical instrumentation.

On behalf of the Conference committee, and execution committee of show, I want to thank organizers.

Concurrent Meetings: Tokyo Conferences organized by
Japan Analytical Instruments Manufacturers Association (JAIMA)
& The Japan Society for Analytical Chemistry (JSAC)

Co-sponsors: Association of Examination and Inspection for Supplied Water
National Metrology Institute of Japan / National Institute of Advanced Industrial Science and Technology (NMIJ/AIST)
AOAC International Japan Section
Department of Advanced Measuring Technology Office of Basic Research, JST
Division of Molecular Electronics and Bioelectronics (M&BE), The Japan Society of Applied Physics
Japan Environmental Measurement & Chemical Analysis Association
Metabolic Profiling Forum
National Institute for Materials Sciences (NIMS)
Organization for Research and Communication on Environmental Risk of Chemicals
Professionals' Net Work in Advanced Instrumentation Society
Terahertz Technology Forum
The Biometrics / characterizations forum in SNTT(The Society of Non-traditional Technology)
The Japan Society for Analytical Chemistry (JSAC)
The Japanese Society of Microscopy
The Japanese Standards Association ;Japan National Committee for Standardization of Surface Chemical Analysis (JSCA)
The Science News Ltd.
The Spectroscopical Society of Japan

* Sessions are conducted in Japanese.

JAIMA FORUM 2007

“Instrumental Analysis will enhanced old fine art studies in historical culture investigation”

Organizer: Japan Analytical Instruments Manufacturers' Association

Date: August 29 (Wed.) 13:00~16:30

Place: Convention Hall B, International Conference Hall, Makuhari Messe

Advance registration system

13:00~13:05

Opening Remark

Chairman: Hideaki KOIZUMI (Advanced Research Laboratory, Hitachi Ltd.)

13:05~14:00

Analytical Techniques used for Conservation and Restoration of Cultural Properties

Yasuhiro HAYAKAWA

(Center for Conservation Science and Restoration Techniques,
National Research Institute for Cultural Properties, Tokyo)

14:00~14:45

Kazuo TANIGUCHI

(Osaka Electro-Communication University)

14:45 ~ 15:00 (Break)

15:00~15:45

Susumu SHIMOYAMA

(Kibi International University)

15:45~16:30

Terahertz spectroscopy for material analyses of western art work

Kaori Fukunaga

(National Institute of Information and Communications Technology)

August 28(Tue.) Morning

◆“23-th Symposium on Analytical Electron Microscopy” (1/2)

Organizer: The Japanese Society of Microscopy

Date: August 28 (Thu.) 10:00~17:00

Place: International Conference Room, 2nd Floor of International Conference Hall

Admission fee: ¥6000 for Members, ¥7000 for General, Free for Students

Advance registration system: Necessity

10:00~12:00	Tutorial Session:	
	Energy Dispersive X-ray Spectrometry (EDS)	Z. Horita (Kyushu Univ.)
	Electron Energy-Loss Spectroscopy (EELS)	T. Oikawa (JEOL)
	Scanning Transmission Electron Microscopy (STEM)	E. Abe (Univ. of Tokyo)
13:00~15:00	Topics I: Application on New 3-Dimensional Analytical Technique	
	Three-dimensional electron tomography for material characterization	K. Kaneko (Kyushu Univ.)
	New progress on three-dimensional structural analysis	T. Yaguchi (Hitachi High-Tech.)
	Three-dimensional structural analysis in materials science	K. Jinnai (Kyoto Inst. of Tech.)
	X-ray absorption microtomography and its application	H. Toda (Toyohashi Univ. of Tech.)
15:00~17:00	Topics II: Advanced Analysis Method and Its Application	
	Spherical aberration corrector for analytical electron microscopy (AEM)	E. Okunishi (JEOL)
	Low voltage SEM as a part of voltage optimized imaging	S. Tachibana (SII Nano Tech.)
	Electron holography and its application	T. Hirayama (JFCC)
	Crystal structure and charge density analysis using convergent-beam electron diffraction	K. Tsuda (Tohoku Univ.)

August 28(Tue.) Afternoon

◆Organic and Bio SPM Workshop 2007 (1/2)

Organizer: Division of Molecular Electronics and Bioelectronics (M&BE), The Japan Society of Applied Physics

Date: August 28 (Tue) 13:00 ~ 19:00

Place: Meeting room 201, 2nd Floor of International Conference Hall

Admission fee: Pre-registration: ¥1000 (M&BE members); ¥3000 (Individual members of JSAP and supporting Societies); ¥5000 (Non-members); ¥1000 (Students);

Advance registration system: On-site registration is also available with admission fees of ¥3000; ¥6000; ¥8000; ¥2000, respectively

Please see the following homepages(Japanese) about details.

<http://annex.jsap.or.jp/support/division/MandBE/sym/index.html>

13:00~13:45	Ken-ichi Fukui (Tokyo Institute of Technology)
13:45~14:30	Ken Nakajima (Tokyo Institute of Technology)
14:30~15:15	Naruo Sasaki (Seikei University)
15:15~16:00	Takashi Tokizaki (Advanced Industrial Science and Technology)
16:10~17:00	Manufacturer technology introduction
17:00~19:00	Poster session / short presentation

◆Seminar for Instruments Analyst

“Best practice for Chemical Analysis by HPLC in advanced analytical lab”

Organizer: Professionals' Net Work in Advanced Instrumentation Society (PAI-NET)

Date: August 28 (Tues) 13:00~17:00

Place: Meeting room 302, 3rd Floor of International Conference Hall

Admission fee: ¥8,400

Advance registration system

13:00~13:10	Opening Address	Masaaki SENDA (PAI-NET)
	Best practice for Chemical Analysis:	
13:10~14:40	1. Chemical analysis for cosmetics and non-authorized medicine: best selection from columns, solvent, instruments	
	Shigeyuki KOIKE(Former chief researcher of chemical analytical center of Lion Corporation)	
14:40~15:00	(Break)	
15:00~16:30	2. Chemical Analysis for food and authorized medicine: how to assure the credibility of quantitative data; case study of operation procedure	
	Hideo HASEGAWA(Former director of food science Lab of Meiji Dairies Corporation)	
16:30~17:00	Questions and Answers	

◆Seminar for beginners

“The latest topics in overseas instrument analysis markets reported in the field”

Organizer: Professionals' Net Work in Advanced Instrumentation Society (PAI-NET)

Date: August 28 (Tues) 13:00~16:50

Place: Meeting room 303, 3rd Floor of International Conference Hall

Admission fee: ¥8,400

Advance registration system

13:00~13:10 Greeting

13:10~14:00 **China struggle with environmental pollution**

14:00~14:40 **Case study of RoHS test in China**

Takao SEGAWA (X-TEC Corporation)

14:40~15:00 (Break)

15:00~15:50 **Instrumental Analysis activity in Thailand**

Hiroyuki KURUMIYA (Adviser, Department of Environmental Quality Promotion (**DEQP**))

15:50~16:30 **Technology Trend in Analytical instrumentation in USA; the report of Pittcon**

Takeshi MURAYAMA ((PAI-NET))

16:30~16:50 Questions and Answers

August 29(Wed.) Morning

◆“23-th Symposium on Analytical Electron Microscopy”

Organizer: The Japanese Society of Microscopy

Date: August 29 (Wed.) 10:00~17:00

Place: International Conference Room, 2nd Floor of International Conference Hall

Admission fee: ¥6000 for Members, ¥7000 for General, Free for Students

Advance registration system: Necessity

10:00 ~ 12:00	New Progress on Sample Preparation:	
	FIB specimen preparation for TEM analyses	T. Kato (JFCC)
	Sample preparation technique for analytical TEM	K. Asayama (Renesas Tech.)
	Defect free specimen finish for HRTEM observation by the use of laser light	H. Ichinose (Riken)
	Specimen preparations for analytical electron microscopic observations in hard tissues	N. Nagaoka (Okayama Univ.)
13:30 ~ 14:30	General Presentation I:	
14:45 ~ 15:45	General Presentation II:	
16:00 ~ 17:00	Invited Talk:	
	Current status and view in the future on analytical instruments	Y. Nihei (Tokyo Univ. of Science)

◆“Metabolic Profiling and Metabolomics”

Organizer: Metabolic Profiling Forum (Tadashi Nemoto <tadashi.nemoto@aist.go.jp>)

Co-Sponsor: Advanced Industrial Science and Technology (AIST)

Support: Japan Human Proteome Organization (JHUPO)

Date: August 29 (Wed.) 10:00~17:00

Place: Convention Hall A, 2nd Floor of International Conference Hall

Admission fee: Free

E-mail registration recommended : mail to <sunaga-eri@aist.go.jp> (Deadline : August 17 (Fri.))

- 10:00~10:05 **Opening remarks**
Mr. Kenji Kojima (JAIMA, Technical Affairs Committee)
- 10:05~10:35 **Technical seminar**
“Utilizing GC and GCxGC coupled with Time-of- Flight Mass Spectroscopy (TOFMS) for the analysis of metabolomics samples”
Dr. Mark Libardoni (LECO, Technical Director)
- 10:35~11:15 **Metabolic syndrome in companion animals: Research trend and development of metabolomics in veterinary science**
Prof. Dr. Kinya Katayama (Department of Veterinary Science Nippon Veterinary and Life Science University)
- 11:15~11:55 **Attempt at metabolic profiling using ultra high-field NMR with cryo-probe and some topics from CRO business side**
Dr. Ken Kawaguchi (Biological Science Labs., Toray Research Center, Inc.)
- 11:55~13:10 **Luncheon seminar**
ALICE2 for Metabolome, Chenomx, SIMCA-P, Profiler etc.
Environmental Research Center, Infocom, JEOL, JEOLDTM, LECO, SHIMADZU, Toray Research Center etc.
- 13:10~13:50 **Omics , biomarkers and clinical oncology**
Mr. Jotaro Kozaki (Editor in Chief NikkeiMedical CancerReview Nikkei Medical Publications, Inc.)
- 13:50~14:20 **Hope and scope in metabolic profiling**
Dr. Tadashi Nemoto (AIST)
- 14:20~15:00 **Attempt to figure the life style-based diseases and Chronic Kidney Disease (CKD) using metabolome analysis**
Prof. Dr. Kazuhisa Takeuchi (Graduate School of Pharmaceutical Sciences, Tohoku University)
- 15:00~15:40 **Challenge for metabolomics utilizing NMR, FT-ICR-MS and IT- TOF-MS**
Prof. Dr. Hiroyuki Wariishi (Bio-Architecture Center, Kyushu University)
- 15:40~16:20 **Bioinformatics by statistical pattern recognition**
Prof. Dr. Yoshihiko Hamamoto (Graduate School of Medicine, Yamaguchi University)
- 16:20~16:50 **Practical solution for metabolic profiling with small numbers of samples**
Mr. Itiro Ando (Environmental Research Center Ltd.)

Vendors' Exhibition : Infocom, Toray Research Center, JEOLDTM, AIST

◆Organic and Bio SPM Workshop 2007 (2/2)

Organizer: Division of Molecular Electronics and Bioelectronics (M&BE), The Japan Society of Applied Physics

Date: August 29 (Wed) 9:00 ~ 13:00

Place: Meeting room 201, 2nd Floor of International Conference Hall

Admission fee: Pre-registration: ¥1000 (M&BE members); ¥3000 (Individual members of JSAP and supporting Societies); ¥5000 (Non-members); ¥1000 (Students);

Advance registration system: On-site registration is also available with admission fees of ¥3000; ¥6000; ¥8000; ¥2000, respectively

Please see the following homepages(Japanese) about details.

<http://annex.jsap.or.jp/support/division/MandBE/sym/index.html>

9:00 ~ 9:45	Tomoji Kawai (Osaka University)
9:45 ~ 10:30	Tatsuo Ushiki (Niigata University)
10:45 ~ 11:15	Atsushi Ikai (Tokyo Institute of Technology)
11:30 ~ 12:15	Shinji Kaminura (University of Tokyo)
12:15 ~ 13:00	Chikashi Nakamura (Advanced Industrial Science and Technology)

◆Tokyo Conference 2007

Plenary Symposium:

Current Topics of ISO/TC 229, Comprehensive Nano-tech Related Regulations

Organizer: Japan Analytical Instruments Manufactures Association(JAIMA) and The Japan Society for Analytical Chemistry(JSAC)

Date: August 29(Wed) 9:30 ~ 12:30

Place: Meeting room 302, 3rd Floor of International Conference Hall

Admission fee: Advance registration ¥ 3,000 On-site registration ¥ 4,000 One-day registration ¥ 2,000

Advance registration system: Please contact Secretariat of Tokyo Conference 2007 tokyoconf@icl.tu-ac.jp

9:30 ~ 9:40	Tokyo Conference 2007 Opening Ceremony	Takehiko Kitamori (Steering Committee, Chairman, University of Tokyo)
9:40 ~ 9:50	Greeting	Hiroshi Iwano (Director, Nonferrous Metals & Fine Ceramics Office, METI)
9:50 ~ 10:20	International Activities on Nanotechnologies Standardization	Akira ONO (AIST)
10:20 ~ 10:40	The Activities of ISO/TC229 WG2 (Measurements & Characterization)	Kazuyoshi Furuta (Seiko Instruments Inc.)
10:40 ~ 11:00	To be confirmed	Morio Yumura (AIST)
11:10 ~ 11:30	Perspectives on R&D of Carbon Nanotubes in Japan and USA	Teruo Yagishita (Nanotechnology Business Creation Initiative)
11:30 ~ 11:50	Latest Technologies for Measurement of Airborne Nanoparticles	Hironu Sakurai (AIST)
11:50 ~ 12:10	Advanced Techniques for Size Measurements of Nano Particles in Solution	Kayori TAKAHASHI (AIST)
12:10 ~ 12:30	MEMS Technology Trend and Related Government Policies	Hiroaki Okahashi (METI)

◆Seminar of New Technology and Products

Organizer: Japan Analytical Instruments Manufacturers' Association

Date: August 29(Wed) 10:30~16:55

Place: Tokyo Bay "Makuhari" Halls 1~12, APA Hotel & Resorts Tokyo Bay "Makuhari"

STELLA, MAI and SHO, Hotel New Otani Makuhari

August 29(Wed.) Afternoon

◆Tokyo Conference 2007 Oral session

Organizer: Japan Analytical Instruments Manufactures Association(JAIMA) and The Japan Society for Analytical Chemistry(JSAC)

Date: August 29(Wed) 15:00 ~ 17:30

Place: Meeting room 302, 3rd Floor of International Conference Hall

Admission fee: Advance registration ¥ 3,000 On-site registration ¥4,000 One-day registration ¥ 2,000

Advance registration system: Please contact Secretariat of Tokyo Conference 2007 tokyoconf@icl.tu-ac.jp

15:00~17:30 Oral session of Tokyo Conference 2007

◆The 22th Workshop of Biometrics / characterizations forum “Biometrology of Foods”

Organizer: The Biometrics / characterizations forum in SNITT(The Society of Non-traditional Technology)

Date: August 29 (Wed.) 13:00~17:00

Place: Meeting room 301, 3rd Floor of International Conference Hall

Admission fee: Textbook ¥3,000

Advance registration system

13:00 ~ 13:10 Opening Address

13:10 ~ 14:00 **“Large-scale genome sequencing of human gut microbiomes”** M. Hattori (The University of Tokyo)

14:00 ~ 14:50 **“Visualization of Food Tasty and Safety”**
J.Sugiyama (National Food Research Institute, National Agriculture and Food Research Organization)

14:50 ~ 15:25 (Break)

15:25 ~ 16:15 **“Kansei Nano-Biosensor”** K.Toko (Kyushu University)

16:15 ~ 16:50 Discussion

16:50 ~ 17:00 Closing Address

◆Tokyo Conference 2007

Automation of Chemical Analysis by Flow Injection Techniques

Organizer: Japan Analytical Instruments Manufactures Association(JAIMA) and The Japan Society for Analytical Chemistry(JSAC)

Date: August 29(Wed) 13:00 ~ 16:00

Place: Meeting room 303, 3rd Floor of International Conference Hall

Admission fee: Advance registration ¥ 3,000 On-site registration ¥ 4,000 One-day registration ¥ 2,000

Advance registration system: Please contact Secretariat of Tokyo Conference 2007 tokyoconf@icl.tu-ac.jp

- 13:00 ~ 13:30 **Principle of Flow-based Techniques for Chemical Analysis** T. Sakai (Aichi Institute of Technology)
- 13:30 ~ 14:20 **Development of Computer-Assisted Flow Chemical Analyzer for Ultra-Trace Metal Analysis: Application to Spectroscopy**
S. Motomizu (Okayama University)
- 14:20 ~ 15:00 **Environmental Restrictions and Flow Injection Analysis of Toxic Metals** K. Oguma (Chiba University)
- 15:00 ~ 16:00 **Demonstration of FIA techniques for Environmental Samples**
N. Teshima (Aichi Institute of Technology) and K. Higuchi (Ogawa & Co.)

◆Actual Status and Future Prospect of Terahertz Time-Domain Spectroscopy from Industrial Point of View.

Organizer: Terahertz Technology Forum

Date: August 29 (Wed.) 13:00~17:00

Place: Meeting room 304, 3rd Floor of International Conference Hall

Advance registration system

- 13:00 ~ 3:10 Introduction Norihisa Hiromoto (Shizuoka Univ.)
- 13:10 ~ 13:35 **Product development of a compact THz-TDS system**
Keiko Kitagishi (tsuka Electronics Co. Ltd.)
- 13:35 ~ 14:00 **Development of terahertz sensor devices and applications for biological sensing**
Toshihiko Ouchi (anon Inc. Canon Research Center)
- 14:00 ~ 14:25 **Real-time imaging using terahertz waves**
Hironori Takahashi (Central Research Laboratory, Hamamatsu Photonics K.K.)
- 14:25 ~ 14:50 **Femtosecond fiber laser system for THz applications** Hideyuki Ohtake (AISIN SEIKI, Co., Ltd.)
- 14:50 ~ 15:05 Coffee Break
- 15:05 ~ 15:30 **A look into the future trend in THz spectrometer from an industrial point of view**
Ryoichi Fukasawa (Spectra Design Ltd.)
- 15:30 ~ 15:55 **THz spectroscopy : a new technique for the analysis of industrial materials**
Ryoichi Kumazawa (Toray Research Center Inc.)
- 15:55 ~ 16:20 **Industrial Applications of Aispec Versatile THz-TDS** Atsuko Ikeda (Aispec)
- 16:20 ~ 16:45 **Terahertz and Far-Infrared spectroscopic solution for Pharmaceutical Application from Bruker Optics.**
Daisuke Sasakura (Bruker Optics K.K.)

August 30(Thurs) Morning

◆Strategic Policy symposium by The Science News Ltd

Organizer: The Science News, Ltd.

Date: August 30 (Thurs) 10:00~12:00

Place: Convention Hall A, 2nd Floor of International Conference Hall

Admission fee: Free

Advance registration system

10:00~10:40 **The New innovation policy in JAPAN; Measurement technology will be helped innovation**

Tateo Arimoto (Director General, Research Institute of Science and Technology for Society, JST and Vice president, Center for Research and Development Strategy, JST)

10:40~12:00 **Innovation25**

Michihiko IWAHASHI(Vice-Minister for Policy Coordination)
Yoshiyuki CHIHARA(Planning and Evaluation Division,
Science and Technology Policy Bureau, MEXT)

◆Spectroscopical Society of Japan: The 43rd Summer Seminar "Fluorescence Spectroscopy and Imaging"

Organizer: Spectroscopical Society of Japan

Date: August 30 (Thu) 10:00~17:50

Place: Meeting Room 301, 3rd Floor of International Conference Hall

Admission fee: [General] ¥12,000 (textbook "Fluorescence Spectroscopy and Imaging" included) or ¥9,000 (no textbook included)

[Student] ¥5,000 (textbook "Fluorescence Spectroscopy and Imaging" included) or ¥2,000 (no textbook included)

Pre-registration deadline: 10 August (Check "<http://www.bunkou.or.jp>" for the detail information)

10:00 ~ 10:05 Opening remark

10:05 ~ 11:30 **Fundamental and Application of Fluorescence Spectroscopy**

Koshin Mihashi (Nihon Fukushi Univ.)

11:30 ~ 13:30 Lunch Break

13:30 ~ 15:00 **Fluorescence Correlation Spectroscopy**

Masataka Kinjo (Hokkaido Univ.)

15:00 ~ 16:30 **Confocal Laser Scanning Microscopy**

Naoya Suzuki (Nagoya Univ.)

16:30 ~ 17:50 **Single Molecular Fluorescence Measurement**

Yoshiharu Ishii (JST)

◆Tokyo Conference 2007 Oral session

Organizer: Japan Analytical Instruments Manufacturers Association(JAIMA) and The Japan Society for Analytical Chemistry(JSAC)

Date: August 30(Thu.)10:00 ~ 12:30

Place: Meeting room 302, 3rd Floor of International Conference Hall

Admission fee: Advance registration ¥ 3,000 On-site registration ¥ 4,000 One-day registration ¥ 2,000

Advance registration system: Please contact Secretariat of Tokyo Conference 2007 tokyoconf@icl.tu-ac.jp

10:00 ~ 12:30 Oral session of Tokyo conference 2007

◆Tokyo Conference 2007 “Challenges of Young Analytical Chemists in Industrial Society”

Organizer: Japan Analytical Instruments Manufacturers Association(JAIMA) and The Japan Society for Analytical Chemistry(JSAC)

Date: August 30(Thu)9:30 ~ 15:00

Place: Meeting room 303, 3rd Floor of International Conference Hall

Admission fee: Advance registration ¥ 3,000 On-site registration ¥ 4,000 One-day registration ¥ 2,000

Advance registration system: Please contact Secretariat of Tokyo Conference 2007 tokyoconf@icl.tu-ac.jp

9:30 ~ 10:00 **MALD-MS Let it play!**

Shin-ichirou Kawabata (Shimadzu Corporation, Analytical & Measuring Instruments Division)

10:00 ~ 10:30 **The function of the analysis section in Nissan Chemical Industries, LTD.**

Katsumi Chikama (Nissan Chemical Industries, LTD)

10:30 ~ 10:40 (Break)

10:40 ~ 11:10 **Development of Ion Attachment Mass Spectrometer (IAMS)**

Megumi Nakamura (Canon ANELVA Technix Corporation)

11:10 ~ 11:40 **Development of rapid analysis method of substances regulated by the RoHS directive**

Masahiro Oishi (TDK Corporation, Technology Group, Materials Analysis Center)

11:40 ~ 13:00 (Lunch Time)

13:00 ~ 13:30 **Development of Thermally Evolved Gas Analysis using Mass Spectrometry (EGA-MS)**

Tasashi Arai (Thermal Analysis Group, Strategic Business Unit, Rigaku Corporation)

13:30 ~ 14:00 **Development of continuous monitoring system for gas generation behavior of coke oven**

Masayuki Nishifuji (Advanced technology research lab., Nippon steel corporation)

14:00 ~ 15:00 Poster short oral preview

◆Seminar of New Technology and Products

Organizer: Japan Analytical Instruments Manufacturers Association

Date: August 30 (Thurs) 10:30~16:55

Place: Tokyo Bay “Makuhari” Halls 1 ~11, APA Hotel & Resorts Tokyo Bay “Makuhari”

STELLA, Hotel New Otani Makuhari

August 30 (Thurs) Afternoon

◆Tokyo Conference 2007

Asia Young Analytical Chemist Poster Session

Organizer: Japan Analytical Instruments Manufactures Association(JAIMA) and The Japan Society for Analytical Chemistry(JSAC)

Date: August 30(Thu.) 15:00 ~ 17:00

Place: Meeting room 101, 1st Floor of International Conference Hall

Admission fee: Advance registration ¥ 3,000 On-site registration ¥4,000 One-day registration ¥ 2,000

Advance registration system: Please contact Secretariat of Tokyo Conference 2007 tokyoconf@icl.t.u-ac.jp

15:00 ~ 17:00 Asia Young Analytical Chemist Poster Session

◆20th NMIJ Seminar -Certified Reference Materials for Traceable Measurements-

Organizer: National Metrology Institute of Japan / National Institute of Advanced Industrial Science and Technology (NMIJ/AIST)

Date: August 30 (Thu.) 13:30~16:30 (Doors open at 13:00)

Place: International Conference Room, 2nd Floor of International Conference Hall

Admission fee: Free

Advance registration system: <http://www.nmij.jp/news/event.html> (Only in Japanese)

13:30 ~ 13:40	Introduction	Koichi CHIBA (NMIJ/AIST)
13:40 ~ 13:50	How to Read Certificates of NMIJ-CRMs	Hiroyuki UMEHARA (NMIJ/AIST)
13:50 ~ 14:10	Ultrathin Silicon Oxide Film and GaAs/AlAs Super Lattice	Toshiyuki FUJIMOTO (NMIJ/AIST)
14:10 ~ 14:30	Fine Silicon Nitride Powder	Naoko NONOSE (NMIJ/AIST)
14:30 ~ 14:50	Sulfur in Toluene	Yuko KITAMAKI (NMIJ/AIST)
14:50 ~ 15:10	Cleatinine	Akiko TAKATSU (NMIJ/AIST)
15:10 ~ 15:25	PCB in Oil	Takashi YARITA (NMIJ/AIST)
15:25 ~ 15:40	Heavy Metals (Cd, Cr, Pb, Hg) in ABS Resin	Masaki OHATA (NMIJ/AIST)
15:40 ~ 16:30	Individual Consultation	NMIJ Staffs including lecturers

◆The Prototypes of the Measurement System As the Output of "Development of System and Technology for Advanced Measurement and Analysis, JST"

Organizer:

Date: August 30 (Thurs) 13:00~17:45

Place: Convention Hall A, 2nd Floor of International Conference Hall

Admission fee: Free

Advance registration system

◆JAIMA Symposium "Analytical technique screening method"

Organizer: Japan Analytical Instruments Manufacturers' Association

Date: August 30 (Thu) 13:00~16:30

Place: Convention Hall B, 2nd Floor of International Conference Hall

Admission fee: ¥1,500 (¥1,000 prior-registered participants)

Advance registration system

Chairman: Koji SUZUKI (Science and Technology, Keio University)

Takaho Watanabe (Food and Drug Safety Center)

1. R&D trends of sensors applied to chemical analytical screening test

13:00 ~ 14:00 **Citizen of advanced nations will be used the analytical instrument as safety of life**

Members of the technical affaires committee, JAIMA

2. Foods safety

14:00 ~ 14:30 **Analytical chemistry involved in food safety**

Takaho Watanabe (Food and Drug Safety Center)

14:30 ~ 15:00 **Multiresidue analytical methods of pesticides in food for positive list system introduction**

Satoru Nemoto (National Institute of Health Science)

15:00 ~ 15:30 **Multiresidue Screening Methods for the Determination of Pesticides in Foods**

Yoshichika HIRAHARA (ex-Kobe Quarantine Station)

15:30 ~ 16:00 **Screening Method for Residual Veterinary Drugs in Food**

Masakazu Horie (Saitama Prefectural Institute of Public Health)

16:00 ~ 16:30 **Proficiency Testing for the Chemical Analysis of Food**

Akemi YASUI (Analytical Science Division, National Food Research Institute)

National Agriculture and Food Research Organization)

◆Introduction to Testing Method of Drinking Water

Organizer: Association of Examination and Inspection for Supplied Water

Date: August 30 (Thurs) 13:10~16:00

Place: Meeting room 201, 2nd Floor of International Conference Hall

Admission fee: Members of Association of Examination and Inspection for Supplies ¥4,000 Others ¥ 6,000

Advance registration system

13:10~16:00 ① **Current Movement of Drinking Water Quality Examination and Its New Method**

Prof. Ando

② **Present Situation of Drinking Water Sources and the Improvement of the Function of Purifying Drinking Water Sources**

Prof. Inamori

◆Tokyo Conference 2007

Workshop: Environmental analysis for improving of QOL (Organized by the Discussion Group for Environmental Analyses of JSAC)

Organizer: Japan Analytical Instruments Manufactures Association(JAIMA) and The Japan Society for Analytical Chemistry(JSAC)

Date: August 30(Thu.)13:00 ~ 16:35

Place: Meeting room 302, 3rd Floor of International Conference Hall

Admission fee: Advance registration ¥ 3,000 On-site registration ¥ 4,000 One-day registration ¥ 2,000

Advance registration system: Please contact Secretariat of Tokyo Conference 2007 tokyoconf@icl.tu-ac.jp

13:00 ~ 13:05 Opening Address Kin-ichi Tsunoda (Gunma University)

13:05 ~ 13:55 **Exposure to pollutants in a daily life** Masashi Ono (National Institute for Environmental Studies)

14:00 ~ 14:45 **Analysis for hazardous chemicals relating “sick house syndrome”.**

Takashi Amagai (the University of Shizuoka)

(Intermission)

15:00 ~ 15:45 **Dust mite allergens indoors.** Hideaki Matsuki (Tokai University)

15:50 ~ 16:35 **Present status of asbestos problems in the environment**

Makoto Torigai (Environmental Control Center Co., Ltd.)

◆Open Seminar for The VAMAS Surface Chemical (TWA-2) Activities

Organizer: National Institute for Materials Sciences (NIMS)

Date: August 30 (Thurs) 13:00~17:00

Place: Meeting Room 304, 3rd Floor of International Conference Hall

Contact: S. Fukushima (NIMS) E-mail: fukushima.sei@nims.go.jp TEL: 029-859-2724

13:00 ~ 13:20	TWA-2 report of the recent activities	S. Tanuma (NIMS, Chair)
13:20 ~ 13:40	TWA-2 project A6 - the progress situation Evaluation of uncertainties in XPS peak intensities associated with different techniques and procedures for background subtraction	S. Fukushima (NIMS)
13:40 ~ 14:30	TWA-2 project A9 - the progress situation Automated Peak Detection in XPS Spectra (intermission)	M. Suzuki (Ulvac Phi)
14:50 ~ 15:50	TWA-2 project A7 - the progress situation Evaluation of electron beam damage of SiO₂/Si in Auger microprobe analysis (The quantitative evaluation of sample damage by the electron beam irradiation) Round Robin Study of Evaluation of Electron Beam Damage of SiO₂/Si in Auger Microprobe Analysis	H. Sato (NIMS)
	The study of surface degradation on silicon oxide during electrons irradiation	Y. Mori (NGK Insulators, Ltd)
15:50 ~ 17:00	Open discussion for the standardization The new project proposal Sample degradation of organic material caused during XPS analysis Recent round robin test on the damage of organic materials The new project proposal and open discussion	H. Tohma (Nissan ARC) N. Suzuki (Utsunomiya Univ.) S. Tanuma (NIMS, Chair)

August 31(Fri) Morning

◆2007 Environmental Seminar

Organizer: Japan Environmental Measurement & Chemical Association

Date: August 31 (Fri.) 10:00~15:30

Place: International Conference Room, 2nd Floor of International Conference Hall

Admission fee: Free

Advance registration system

- 10:00 ~ 12:00 **The Chinese food security system which we supposed from agricultural chemicals analysis**
M.Satou (Asia food safety research center co.,)
Break
13:30 ~ 15:30 **About the Dioxin 2007 Tokyo conference**
T.Tkasuga (Shimadu Techno Research co.,)

◆Spectroscopical Society of Japan: The 43rd Summer Seminar "Raman Spectroscopy"

Organizer: Spectroscopical Society of Japan

Date: August 31 (Fri) 10:00~17:50

Place: Meeting Room 301, 3rd Floor of International Conference Hall

Admission fee: [General] ¥12,500 (textbook " Raman Spectroscopy " included) or ¥9,000 (no textbook included)

[Student] ¥5,500 (textbook " Raman Spectroscopy " included) or ¥2,000 (no textbook included)

Pre-registration deadline: 10 August (Check "<http://www.bunkou.or.jp>" for the detail information)

- 10:00 ~ 10:40 **Front Line of Raman Spectroscopy**
Hiro-o Hamaguchi (Univ. Tokyo)
10:40 ~ 12:20 **Fundamental and Practice of Raman Spectroscopy**
Koichi Iwata (Univ. Tokyo)
12:20 ~ 14:20 Lunch Break
14:20 ~ 16:00 **Application of Raman Spectroscopy: Basic Science**
Yukio Furukawa (Waseda Univ.)
16:00 ~ 17:40 **Application of Raman Spectroscopy: Industrial Analysis**
Masanobu Yoshikawa (Toray Research Center)
17:40 ~ 17:50 Closing Remark

◆Tokyo Conference 2007 Oral session

Organizer: Japan Analytical Instruments Manufacturers Association(JAIMA) and The Japan Society for Analytical Chemistry(JSAC)

Date: August 31(Fri.) 9:30 ~ 12:15

Place: Meeting room 302, 3rd Floor of International Conference Hall

Admission fee: Advanced-registration ¥ 3,000 On-site registration ¥4,000 One-day registration ¥ 2,000

Advance registration system: Please contact Secretariat of Tokyo Conference 2007 tokyoconf@icl.tu-ac.jp

<http://www.chem.tu-tokyo.ac.jp/appchem/labs/kitamori/tokyoconf07/index.htm>

9:30 ~ 12:15 **Oral session of Tokyo Conference 2007**

◆Tokyo Conference 2007

Basics in the fundamentals of analytical chemistry (Primary lectures for beginners of analyst)

Organizer: Japan Analytical Instruments Manufacturers Association(JAIMA) and The Japan Society for Analytical Chemistry(JSAC)

Date: August 31(Fri.)10:00 ~ 12:00

Place: Meeting room 303, 3rd Floor of International Conference Hall

Admission fee: Advance registration ¥ 3,000 On-site registration ¥4,000 One-day registration ¥ 2,000

Advance registration system: Please contact Secretariat of Tokyo Conference 2007 tokyoconf@icl.tu-ac.jp

10:00 ~ 11:00 **Reporting analytical values from measured data**

Uemoto Michihisa (Tokyo Metropolitan Industrial Research Institute)

11:00 ~ 12:00 **Reliability and Uncertainties of Analytical Values**

Akiharu Hioki (AIST)

◆Seminar of New Technology and Products

Organizer: Japan Analytical Instruments Manufacturers' Association

Date: August 31 (Fri) 10:30~16:20

Place: Tokyo Bay "Makuhari" Halls 1 ~11, APA Hotel & Resorts Tokyo Bay "Makuhari"

STELLA, MAI, and SHO, Hotel New Otani Makuhari

August 31 (Fri) Afternoon

◆Efficient Chemical Substances Management with Proactive Measurement in Advanced Company

Organizer: Organization for Research and Communication on Environmental Risk of Chemicals

Date: August 31 (Fri.) 13:00 ~ 16:35

Place: Convention Hall A, 2nd Floor of International Conference Hall

Admission fee: ¥3,000 (including reference book)

Advance registration system: Not necessary

- 13:00 ~ 13:10 Opening address
- 13:10 ~ 13:50 **An expectation to Effective Measurement for propulsion of the Best -Mix policy on chemical management system**
Hiroshi Ooki (Institute of Environment and Resource Systems)
- 13:50 ~ 14:20 **Utilization of Effective Measurement in Wastewater Management** Tetsuaki Okada (Fuji Photo Film Co.Ltd.)
- 14:20 ~ 14:50 **Measuring chemicals in Atmosphere around Factory**
Naoatsu Ishizaki (Japan Chemical Industry Association)
- 14:50 ~ 15:20 **Proposal on effective measurements on emission -gas and Atmosphere- monitoring in Factory**
Kohei Urano (Yokohama National Univ.)
- 15:20 ~ 15:35 Break
- 15:35 ~ 16:05 **Effective management on chemical substances in electronic products** Yutaka Iwamoto (SONY Corp.)
- 16:05 ~ 16:35 **Effective management on chemicals substances in Parts -Supply** Kiichi Nakamura (TDK Corp.)

◆JAIMA Symposium

“Accelerated the trend of miniaturization and mobilization in Analytical instruments”

Organizer: Japan Analytical Instruments Manufacturers' Association

Date: August 29 (Wed) 13:00~16:30

Place: Convention Hall B , 2nd Floor of International Conference Hall

Admission fee: ¥1,500 (¥1,000 prior-registered participants)

Advance registration system

- Chairman: Tsuguo SAWADA
- 13:00 ~ 13:10 Opening Remark
- 13:10 ~ 13:55 Jun KAWAI (Kyoto University)
- 13:55 ~ 14:40 **Development and commercialization of handy elemental analyzer**
Yuzuru Takamura (Associate professor, School of materials science, Japan advanced institute of science and technology (JAIST))
Tamotsu Yamamoto (President, Micro emission ltd.)
- 14:40 ~ 15:00 (Break)
- 15:00 ~ 15:45 Katsumi UCHIYAMA (Tokyo Metropolitan University)
- 15:45 ~ 16:30 **Capillary-Assembled Microchip:**
-Towards the development of microfluidic devices capable of multiple diagnosis and drug screening-
Hideaki Hisamoto (Osaka Prefecture University)

◆ **Seminar on the international standardization activity**
"Current Status of the International Standardization for
Surface Chemical Analysis (ISO/TC201) and Microbeam Analysis (ISO/TC202)"

Organizer: The Japanese Standards Association ;

Japan National Committee for Standardization of Surface Chemical Analysis (JSCA)

Date: August 31 (Fri.) 13:00 ~ 16:45

Place: Meeting room 201, 2nd Floor of International Conference Hall

Admission fee: Free

Advance registration system

13:00~13:20	Current activities of nano characterization in ISO/TC229 (Nanotechnology) and the activities of ISO TC201 & TC202	S. Ichimura (AIST)
13:20~13:40	Overview of Present status and the Future of International Standardization for Micro-beam Analysis (ISO/TC202)	H. Kobayashi (Representative of Japanese ISO/TC202)
13:40~14:05	Standardization of EPMA analysis	J. Murayama(Sumitomo Metal Technology, Inc.)
14:05~14:30	Standardization of Analytical Electron Microscopy	S. Hinotani(Sumitomo Metal Technology, Inc.)
14:30~14:55	Standardization of SEM	M. Saito(JEOL Ltd.)
14:55~15:10	(Break)	
15:10~15:30	Current Status and a view of International Standardization for Surface Chemical Analysis (ISO/TC201)	K. Yoshihara(ULVAC-PHI, Inc.)
15:30~15:55	Standardization of surface analysis by AES and XPS	S. Tanuma(NIMS)
15:55~16:20	Standardization of SIMS	Y. Homma(Tokyo University of Science)
16:20~16:45	International Standardization of Scanning Probe Microscopy	D. Fujita(NIMS)

◆Tokyo Conference 2007

Symposium on "Innovation by Analytical Chemistry and Technology"

Organizer: Japan Analytical Instruments Manufactures Association(JAIMA) and The Japan Society for Analytical Chemistry(JSAC)

Date: August 31(Fri.) 13:00 ~ 16:55

Place: Meeting room 302, 3rd Floor of International Conference Hall

Admission fee: Advanced-registration ¥ 3,000 On-site registration ¥ 4,000 One-day registration ¥ 2,000

Advance registration system: Please contact Secretariat of Tokyo Conference 2007 tokyoconf@icl.tu-ac.jp

<http://www.chem.tu-tokyo.ac.jp/appchem/labs/kitamori/tokyoconf07/index.htm>

13:00 ~ 13:15	Introductory Talk	Tsuguo Sawada(JST•Program Officer)
13:15 ~ 13:40	New trends in Japanese innovation policy	Koichi Kitazawa (JST•Senior Executive- Director)
13:40 ~ 14:05	Power & Speed -Global Strategies toward enerating Innovation for Analytical Instrument Manufacturers-	Atsushi Horiba(HORIBA, Ltd. •President and CEO)
14:05 ~ 14:30	Seeing what was unseen	Yoshio Umezawa (Musashino University •Professor,The University of Tokyo, Professor Emeritus)
14:30 ~ 14:55	Innovation & Analytical and Measuring Technology	Shigehiko Hattori (SHIMADZU CORPORATION •President & Chief Executive Officer)
15:00 ~ 15:25	Innovation by Electron microscope	Yoshiyasu Harada (JEOL, Ltd. •President & CEO)
15:25 ~ 15:50	A Front of Synchrotron X-ray Analysis of Materials	Hiroyoshi Suematsu (RIKEN Harima Institute •Director)
15:50 ~ 16:15	Analytical Services and Development of Analysis Technologies	Hideyuki Ishida (Toray Research Center, Inc. •Executive Vice President)
16:15 ~ 16:40	Innovative science & technology for measurement & analysis	Hideaki Koizumi (Hitachi, Ltd. •Corporate Officer, Hitachi, Ltd. & Hitachi Fellow)
16:40 ~ 16:55	Closing address	Hiroki Haraguchi (President of Japan Society for Analytical Chemistry)

◆Tokyo Conference 2007 Closing Ceremony

Organizer: Japan Analytical Instruments Manufactures Association(JAIMA) and The Japan Society for Analytical Chemistry(JSAC)

Date: August 31(Fri.) 17:00 ~ 17:20

Place: Meeting room 302, 3rd Floor of International Conference Hall

17:00 ~ 17:20 Closing Ceremony of Tokyo Conference2007

Koichiro Matsuda (Steering Committee, Vice-Chairman, HORIBA, Ltd.)

◆Tokyo Conference 2007

Seminar of Ion Chromatograph “Lecture for the business experience person”

- First step for using the ion chromatograph well

Organizer: Japan Analytical Instruments Manufactures Association(JAIMA) and The Japan Society for Analytical Chemistry(JSAC)

Date: August 31(Fri.) 13:00 ~ 16:40

Place: Meeting room 303, 3rd Floor of International Conference Hall

Admission fee: Advance registration ¥ 3,000 On-site registration ¥ 4,000 One-day registration ¥ 2,000

Text : ¥1,000

Advance registration system: Please contact Secretariat of Tokyo Conference 2007 tokyoconf@icl.tu-ac.jp

13:00 ~ 13:10	Opening	
13:10 ~ 13:50	“What kind of analysis method is the ion chromatography?”	Yasuyuki Miura (Tokai Uni.)
13:55 ~ 14:30	“Think an appropriate pretreatment method.”	
		Hisomu Nagashima (Nakku Technoservice Corp.)
14:35 ~ 15:10	“How to uses the ion chromatograph well”	Takahiro Suzuki (Nippon Dionex Corp.)
15:25 ~ 16:00	“Water and reagent” is important points for analysis”	Hirohumi Kuroki (Organo Corp.)
16:05 ~ 16:40	“Data and precision control for obtaining the correct value.”	Ryozo Goto (DKK-TOA Corp.)

◆Method Validation- What is it and how to do it.-

Organizer: AOAC International Japan Section

Date: August 31(Fri) 13:00~17:00

Place: Meeting room 304, 3rd Floor of International Conference Hall

Admission fee: Free

Advance registration system: Please send your name, title, contact address to AOACIJS2007@yahoo.co.jp

13:00 ~ 13:30	AOACInternational and AOACInternational Japan Section	
		Takatoshi Moriyama (3M Health Care Limited, President of AOACIJS)
13:30 ~ 15:00	Method Validation for International Acceptance	
		TetsuhisaGoto(Shinshu Univ./AOACOfficial Method Board Member)
15:00 ~ 15:15	Break	
15:15 ~ 15:45	Method Validation for OMA-AOAC	Akio Kitahara(3M Health Care Limited)
15:45 ~ 16:15	Performance Tested Method Validation By AOACRI	Hiroshi Morita, (AZmax, Co.,Ltd.)
16:15 ~ 17:0	Round Table Discussion for Method Validation	All Speakers

JAIMA Conferences 2007Program
August 28 ~ August 31, 2007

Japan Analytical Instruments Manufacturers' Association (**JAIMA**)
Sakura Bldg. 3rd Fl., 1-10-1 Kanda Nishiki-cho, Chiyoda-ku, Tokyo, 101-0054 Japan
Phone: +81-3-3292-0642 Fax: +81-3-3292-7157
E-mail: webmaster@jaima.or.jp

JAIMA SHOW 2008
JAIMA Conference

September 3 ~ September 5, 2008
September 2 ~ September 5, 2008

JAIMA SHOW 2009
JAIMA Conference

September 2 ~ September 4, 2009
September 1 ~ September 4, 2009